

AMERICAN INTERNATIONAL UNIVERSITY BANGLADESH
Faculty of Engineering



Laboratory Report Cover Sheet

Students must complete all details except the faculty use part.

Please submit all reports to your subject supervisor or the office of the concerned faculty.

Laboratory Title: Study of Biasing BJT Biasing Circuit.

Experiment Number: 06 Due Date: 15/11/22 Semester: Fall 22-23

Subject Code: EEE Subject Name: Device LAB Section: C

Course Instructor: Dr. Mohammad Shidugam Degree Program: BSc. EEE

Declaration and Statement of Authorship:

1. I/we hold a copy of this report, which can be produced if the original is lost/ damaged.
2. This report is my/our original work and no part of it has been copied from any other student's work or from any other source except where due acknowledgement is made.
3. No part of this report has been written for me/us by any other person except where such collaboration has been authorized by the lecturer/teacher concerned and is clearly acknowledged in the report.
4. I/we have not previously submitted or currently submitting this work for any other course/unit.
5. This work may be reproduced, communicated, compared and archived for the purpose of detecting plagiarism.
6. I/we give permission for a copy of my/our marked work to be retained by the School for review and comparison, including review by external examiners.

I/we understand that

7. Plagiarism is the presentation of the work, idea or creation of another person as though it is your own. It is a form of cheating and is a very serious academic offence that may lead to expulsion from the University. Plagiarized material can be drawn from, and presented in, written, graphic and visual form, including electronic data, and oral presentations. Plagiarism occurs when the origin of the material used is not appropriately cited.
8. Enabling plagiarism is the act of assisting or allowing another person to plagiarize or to copy your work

Group Number (if applicable): 07 Individual Submission Group Submission

No.	Student Name	Student Number	Student Signature	Date
Submitted by:				
1	<u>Gajjam Hossain Sabut (C)</u>	<u>20-43653-2</u>	<u>Sabut</u>	<u>15-11-22</u>
Group Members:				
2	<u>Junayed Alam Albee (C)</u>	<u>20-99031-2</u>	<u>Albee</u>	<u>15/11/22</u>
3	<u>Ali, Shovon</u>	<u>17-33829-1</u>	<u>Shovon</u>	<u>15/11/22</u>
4	<u>Antu Das</u>	<u>20-44112-2</u>	<u>Antu</u>	<u>4</u>
5	<u>Md. Imtiaz Hossain</u>	<u>19-41203-2</u>	<u>Imtiaz</u>	<u>4</u>
6				

For faculty use only:

Total Marks: _____ Marks Obtained: _____

Faculty comments _____

Title: Study of BJT biasing circuit

Abstract: This experiment is done to establish the proper operating point. It is also done to study the stability of the operating point with respect to changing β in biasing circuit.

Introduction: The operating point of BJT is very important for amplifiers. Since a wrong 'Q' operating point selection increases amplifiers distortion. It is imperative to have a stable 'Q' point, meaning that the operating point should not be sensitive to variation to temperature or BJT β , which can vary widely. In this experiment four different circuits will be analyzed for two different β to check the stability at biasing points.

The analysis of the BJT circuit is a systematic process. Initially, the operating point of a transistor circuit is determined then the small signal BJT model parameters are calculated. Finally, the dc sources are eliminated, BJT model parameters are

calculated. Finally, the sources are eliminated, the BJT is replaced with an equivalent circuit model and the resulting circuit is analyzed to determine the voltage amplification, current amplification, Input impedance, Output Impedance and the phase relation between the input voltage and the output voltage.

Theory and Methodology: The dc analysis is done to determine the mode of operation of BJT and to determine the voltages at all nodes and currents in all branches. The operating point of a transistor circuit can be determined by mathematical or graphical means. Here we will describe only the mathematical solution.

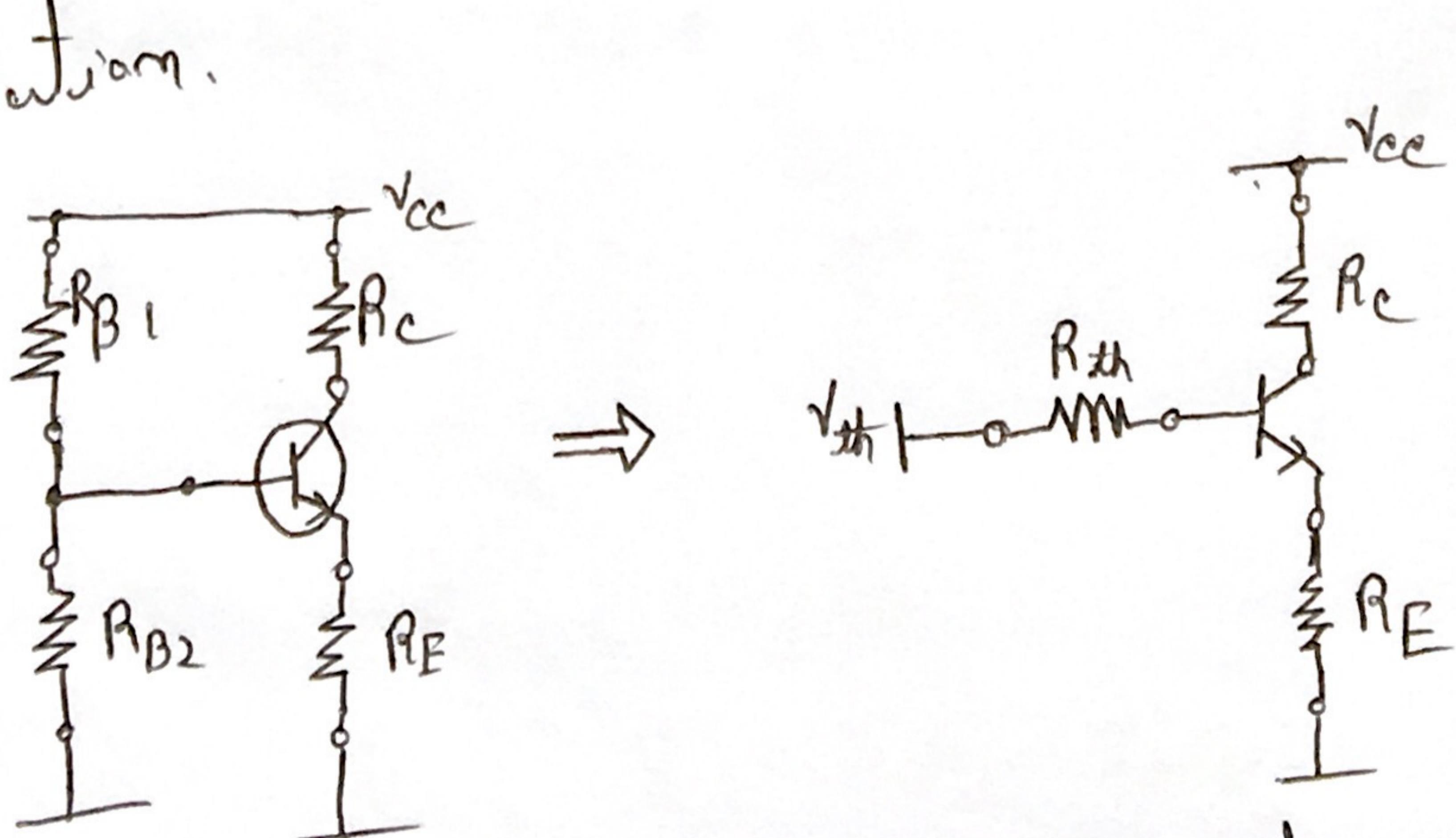


Figure: Biasing Circuit

(3)

We will use the most commonly applied biasing circuit to operate the BJT as an amplifier. A single power supply is used and the voltage divider network consisting of R_{B_1} and R_{B_2} is used to adjust the base voltage. Using the Thevenin equivalent, the voltage divider network is replaced by v_{th} and R_{th} where,

$$v_{th} = \frac{R_{B_2}}{R_{B_1} + R_{B_2}} v_{cc} \quad \text{and} \quad R_{th} = \frac{R_{B_1} R_{B_2}}{R_{B_1} + R_{B_2}}$$

The dc analysis of the circuit is simple by two KVL's at the input and the output loop.

$$v_{th} = I_B R_{th} + R_E I_E + I_E R_E = I_B (R_{th} + (\beta + 1) R_E) + V_{BE}$$

$$v_{cc} = I_C R_C + V_{CE} + I_E R_E = I_C (R_C + \frac{R_{B_2}}{\alpha}) + V_{CE}$$

$$I_B = \frac{V_B - V_{BE}}{R_B + (1 + \beta) R_E}$$

$$I_{CQ} = \beta I_B$$

$$I_{EQ} = (1 + \beta) I_B$$

$$V_{CEQ} = V_{cc} - I_C R_C - I_E R_E$$

(4)

If the BJT is in the active mode the following typical can be observed.

$$V_{BE} \approx 0.7\text{ V} \text{ and } I_C \approx \beta I_B$$

R_C is used to adjust the collector voltage. Finally, R_E is used to stabilize the dc biasing points for different transistor & β can be calculated.

Apparatus:

1) Trainer Board

2) Transistor (C828(NPN), BD135(NPN))

3) Resistors ($R = 22\text{k}\Omega$, $R_C = 470\Omega$, $R_{B1} = 10\text{k}\Omega$, $R_E = 560\Omega$)

4) DC Power supply ($V_{CC} = +15\text{ V DC}$)

5) Multimeter

6) Power supply Cable

Precautions: Transistor are sensitive to be damaged by electrical overloads, heat, humidity and radiation. Damage of this nature often occurs by applying the incorrect polarity voltage to the input circuit. One of the most frequent causes of the transistor is the electrostatic discharge from the human body when the device is handled. The applied voltage, current should not exceed the maximum rating at the given transistor.

Circuit Diagrams:

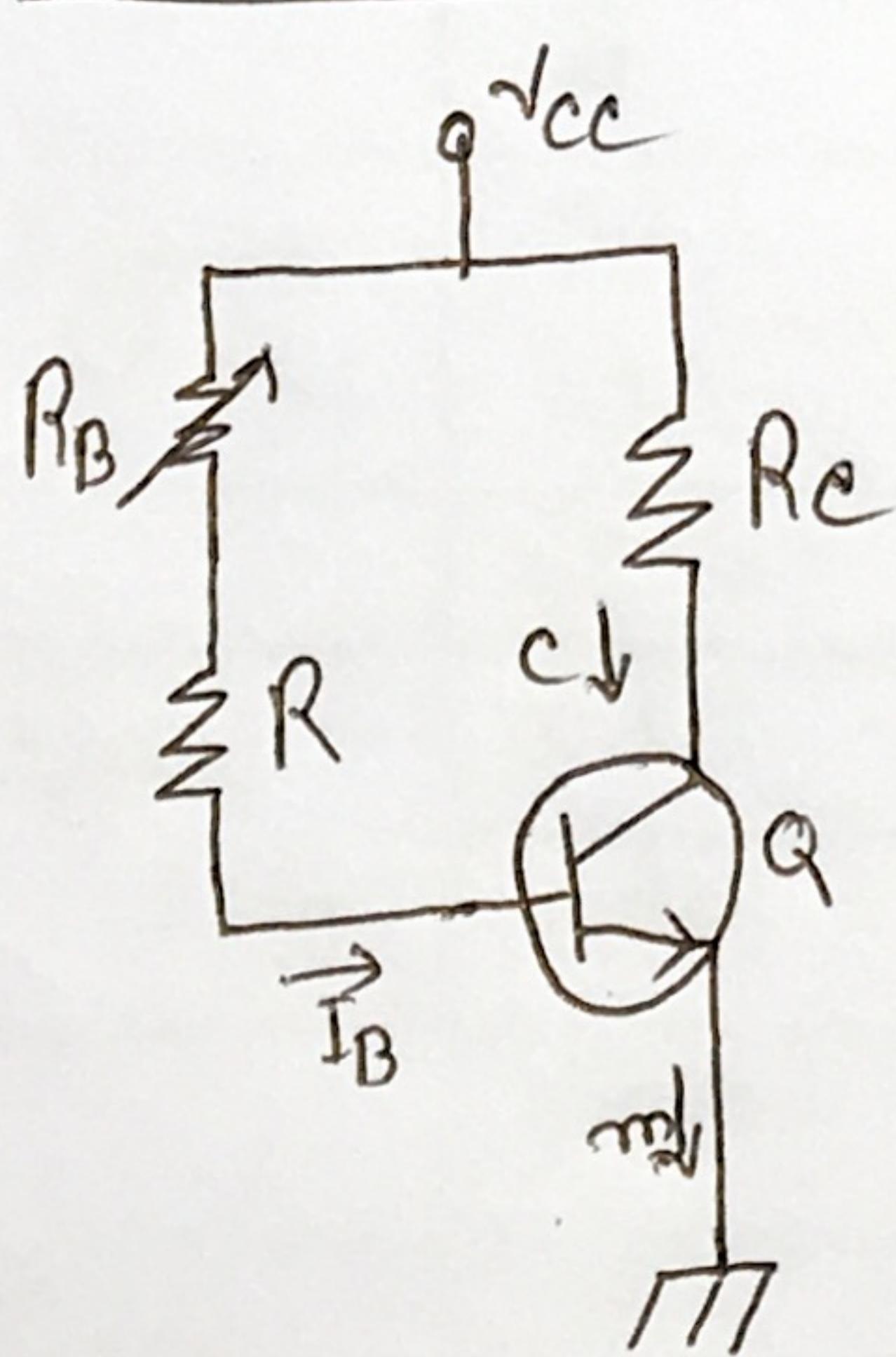


Figure 1(a)

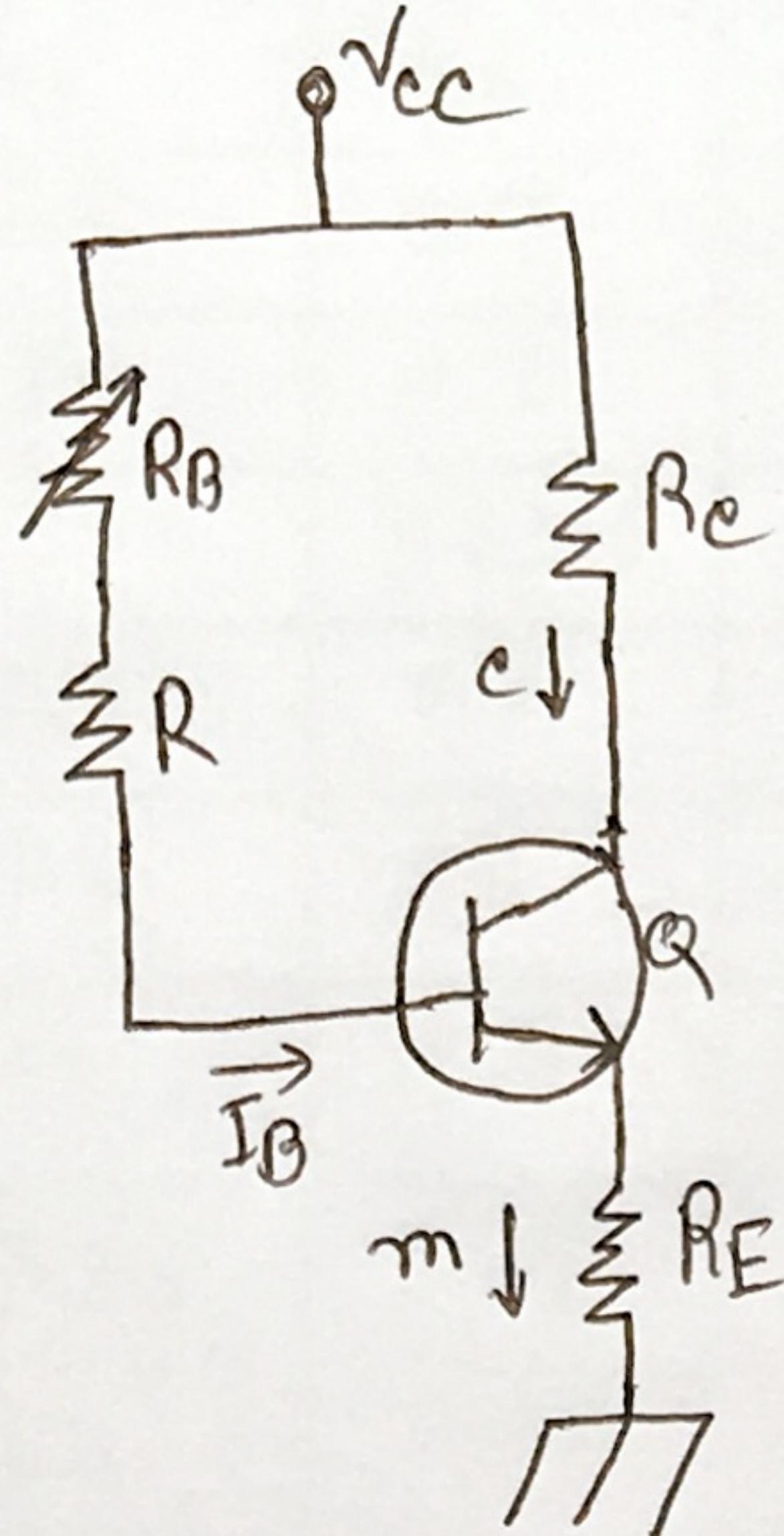


Figure 1(b)

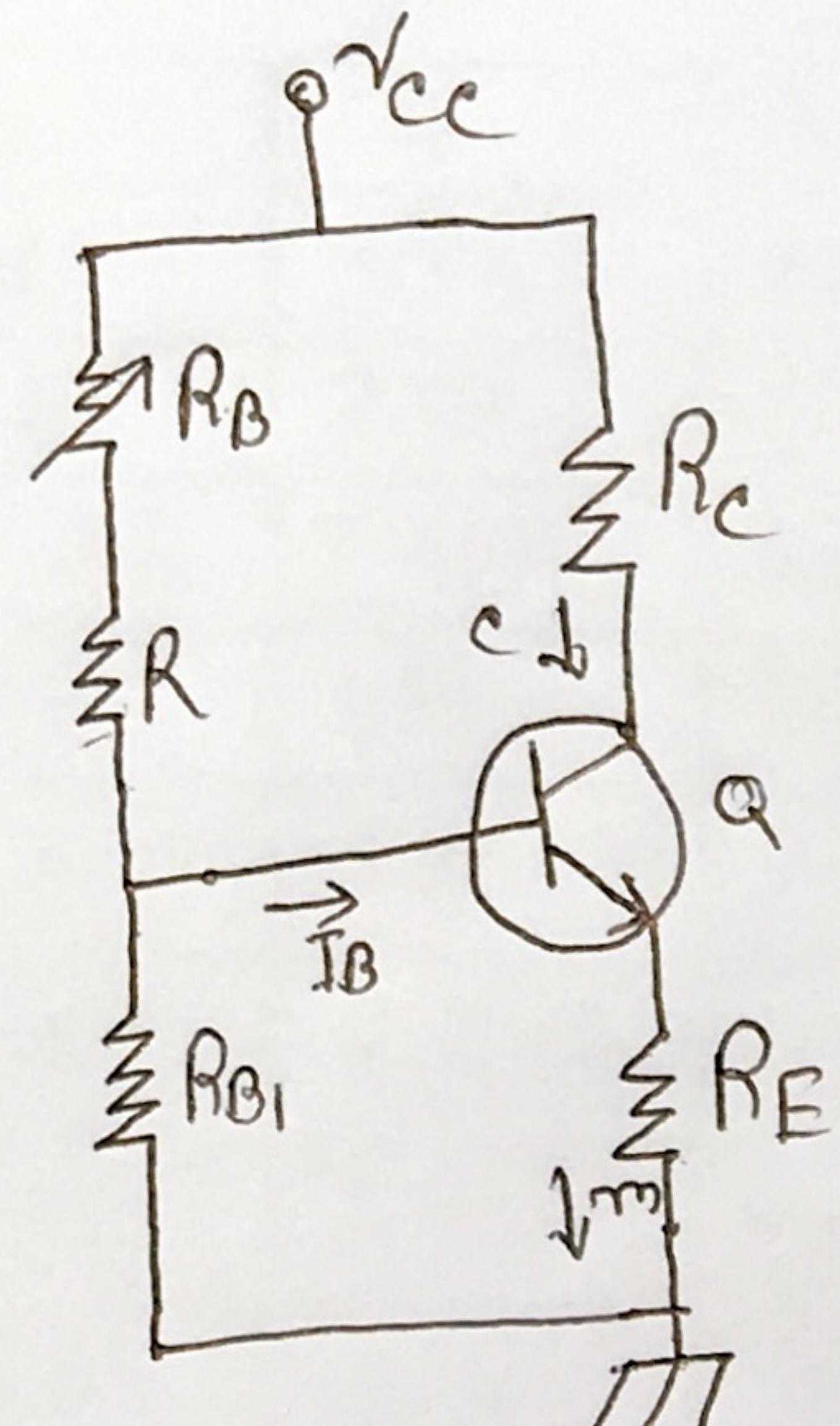


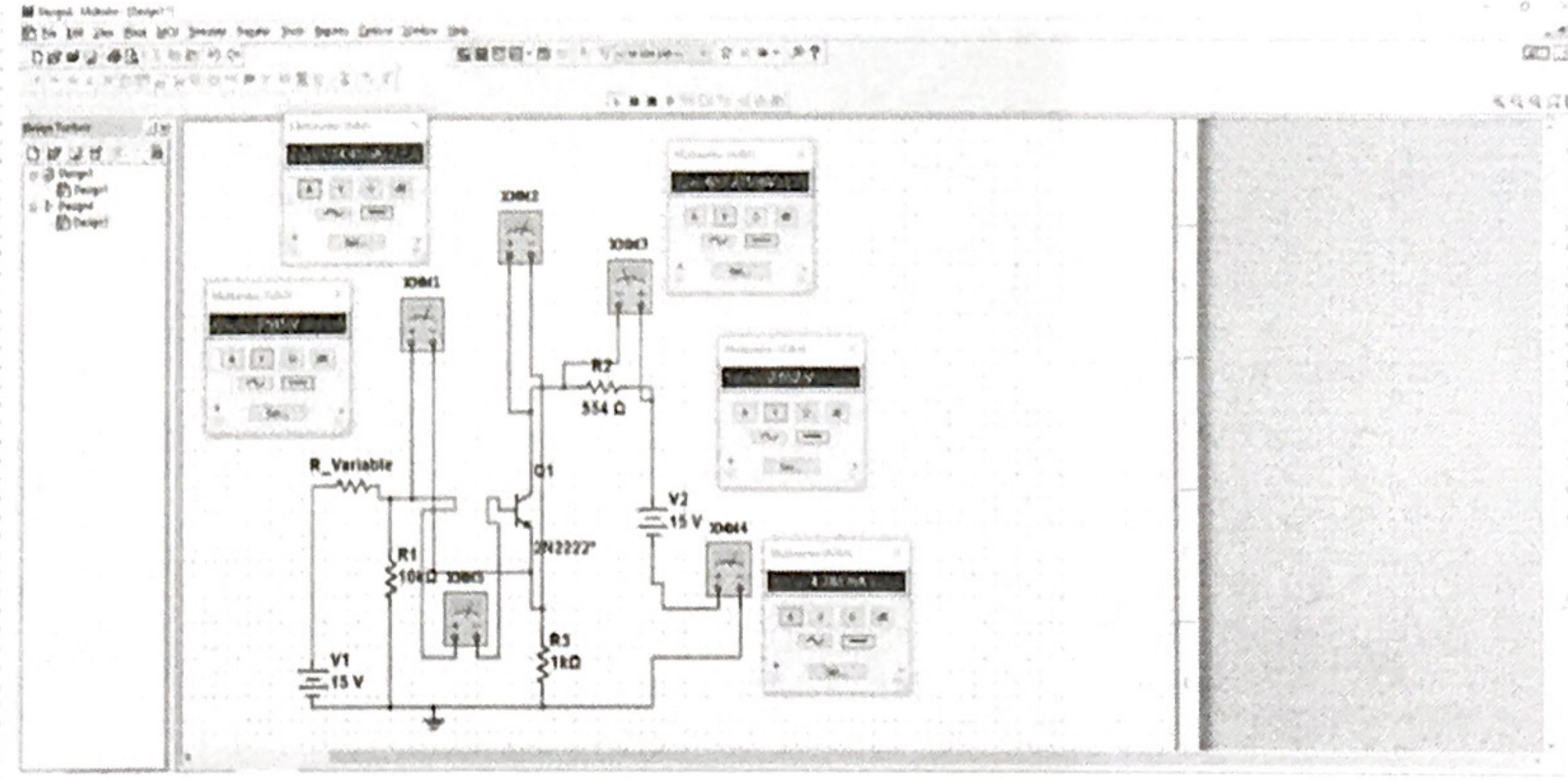
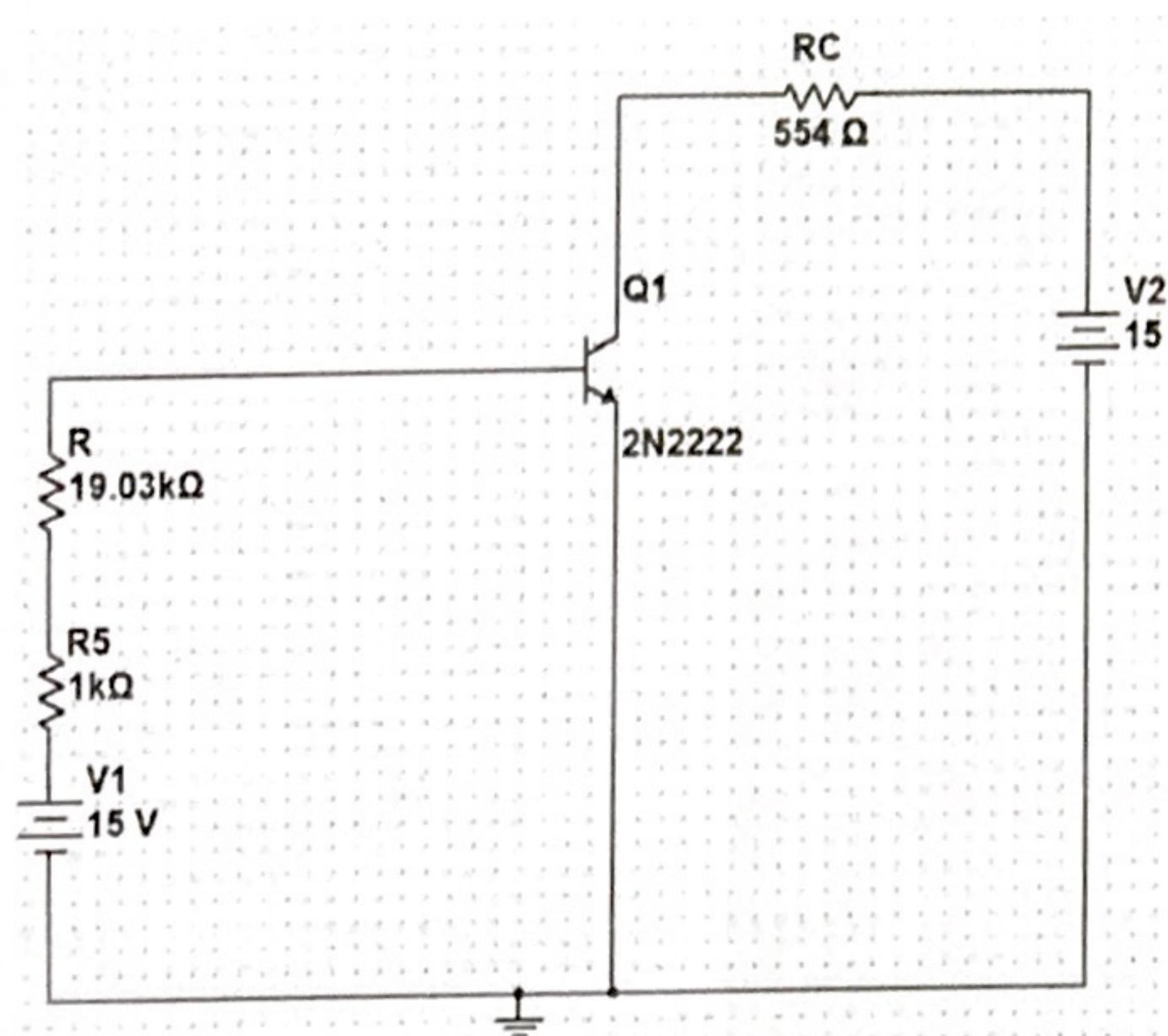
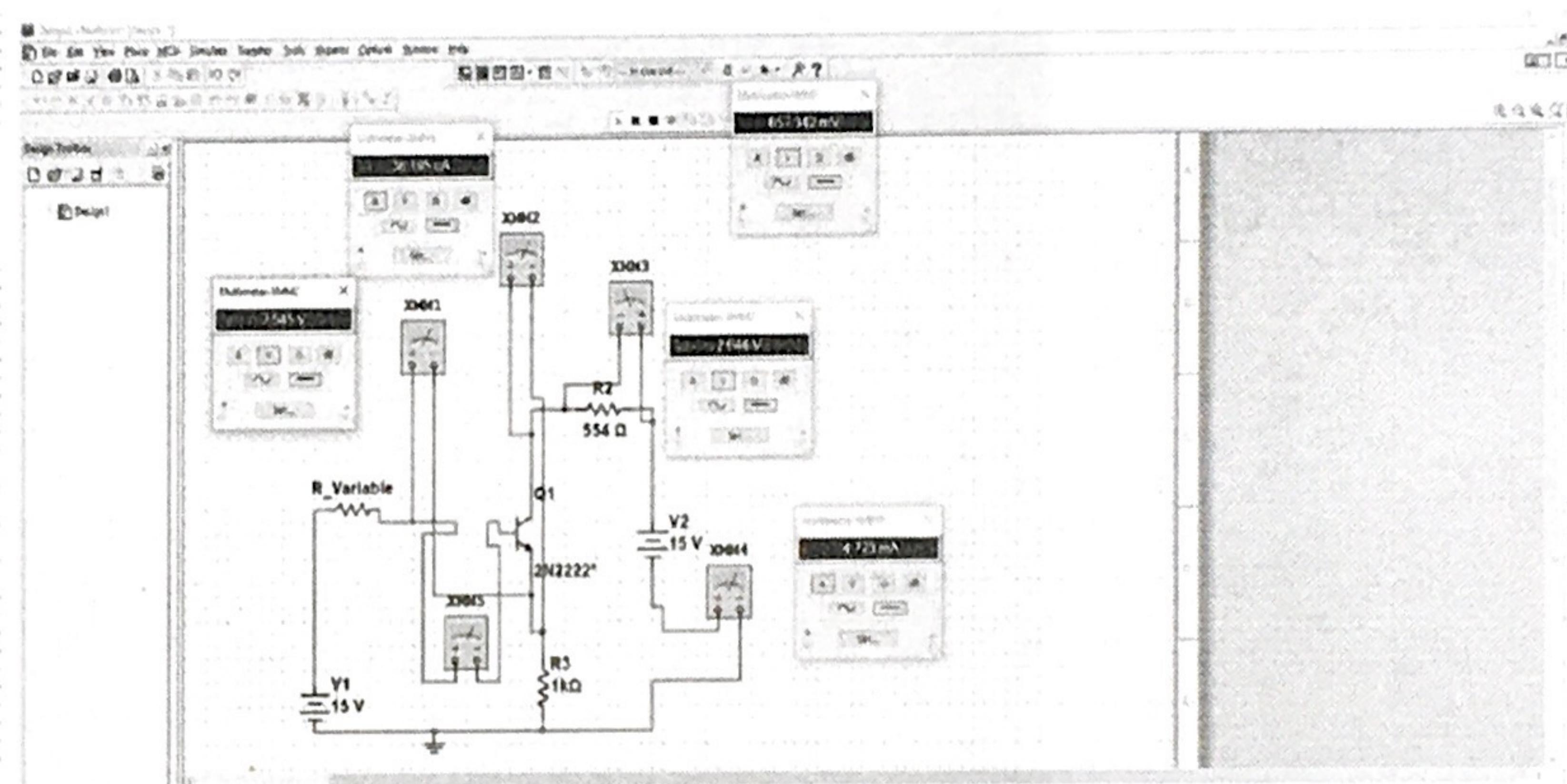
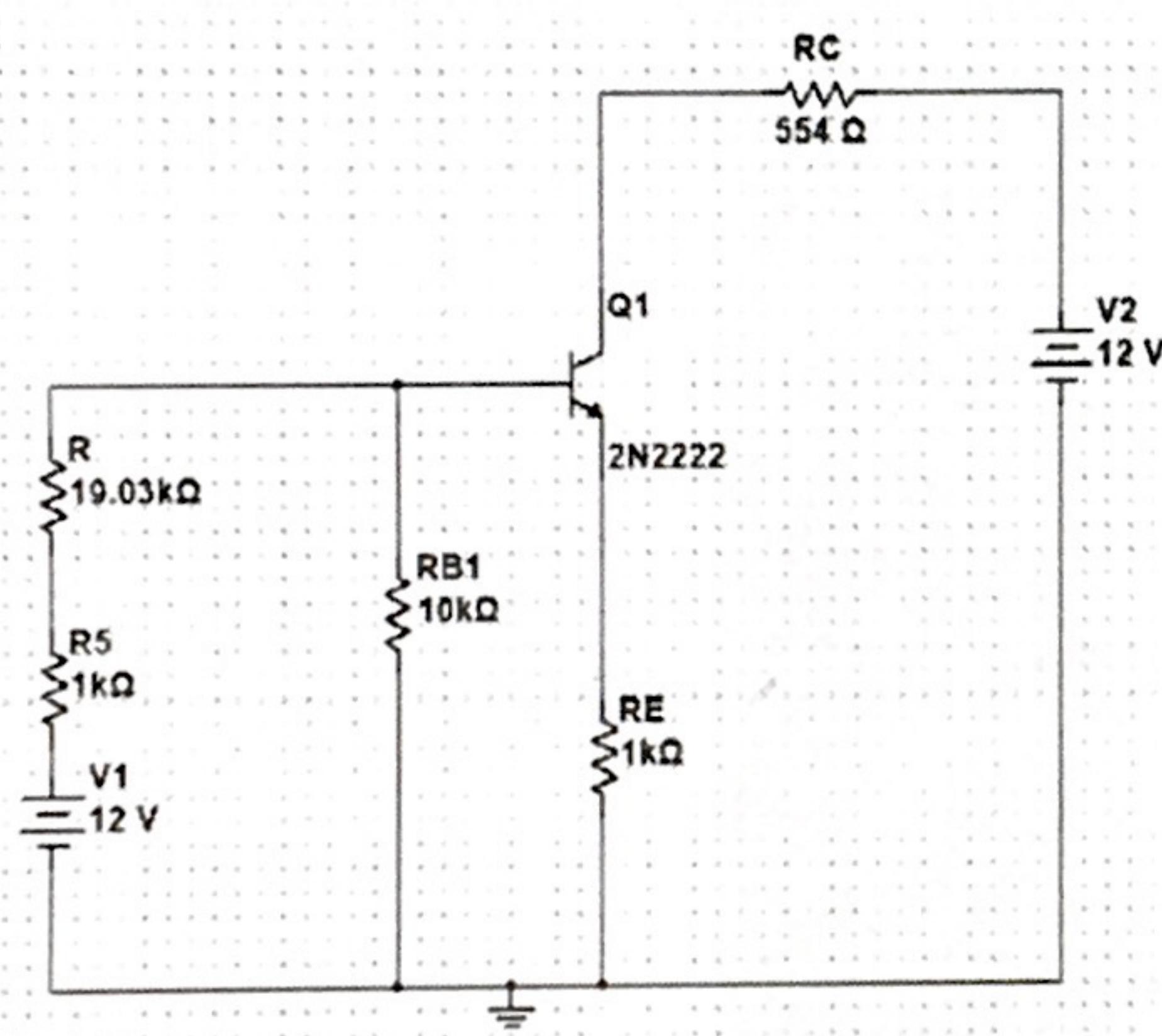
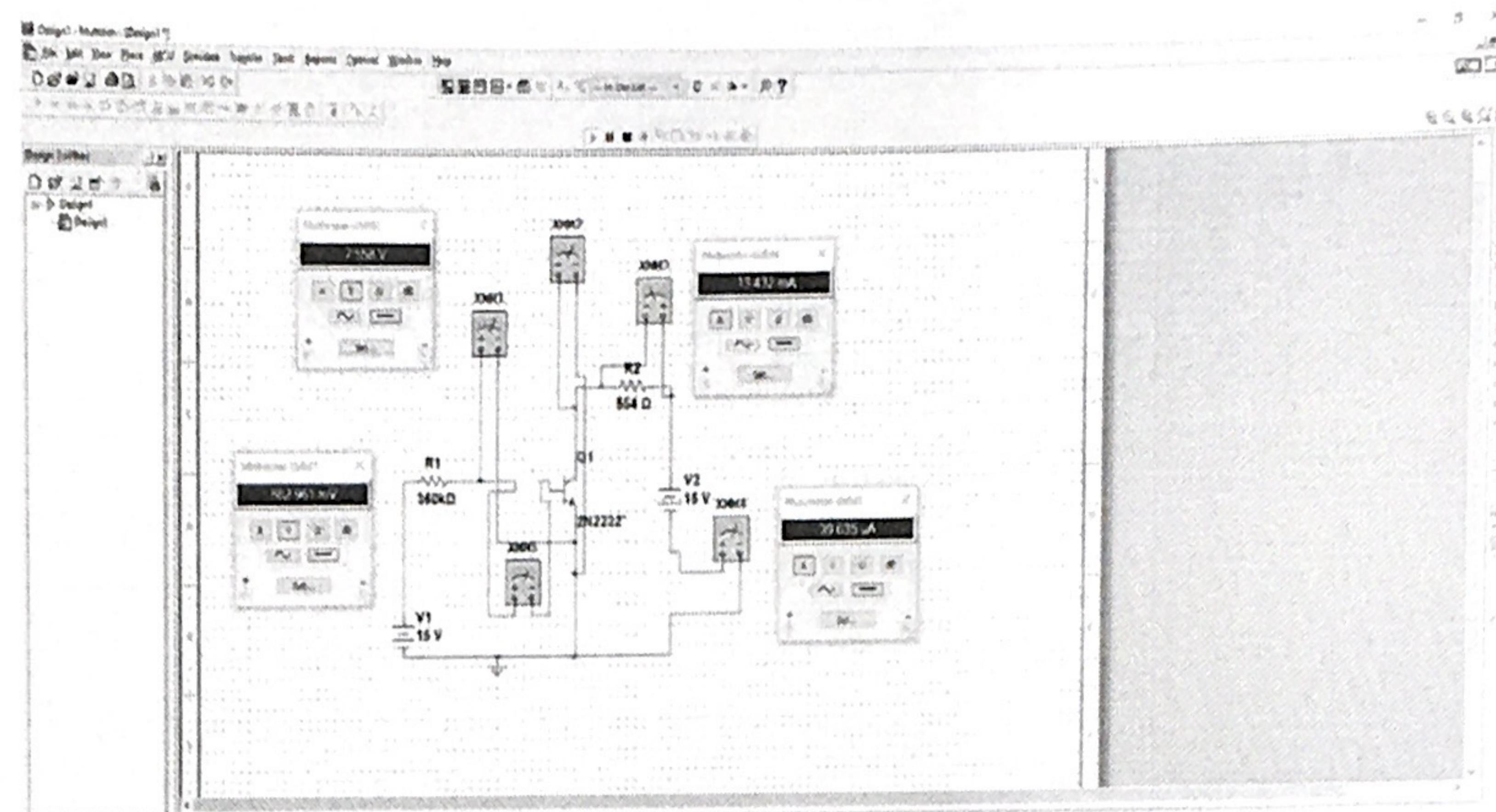
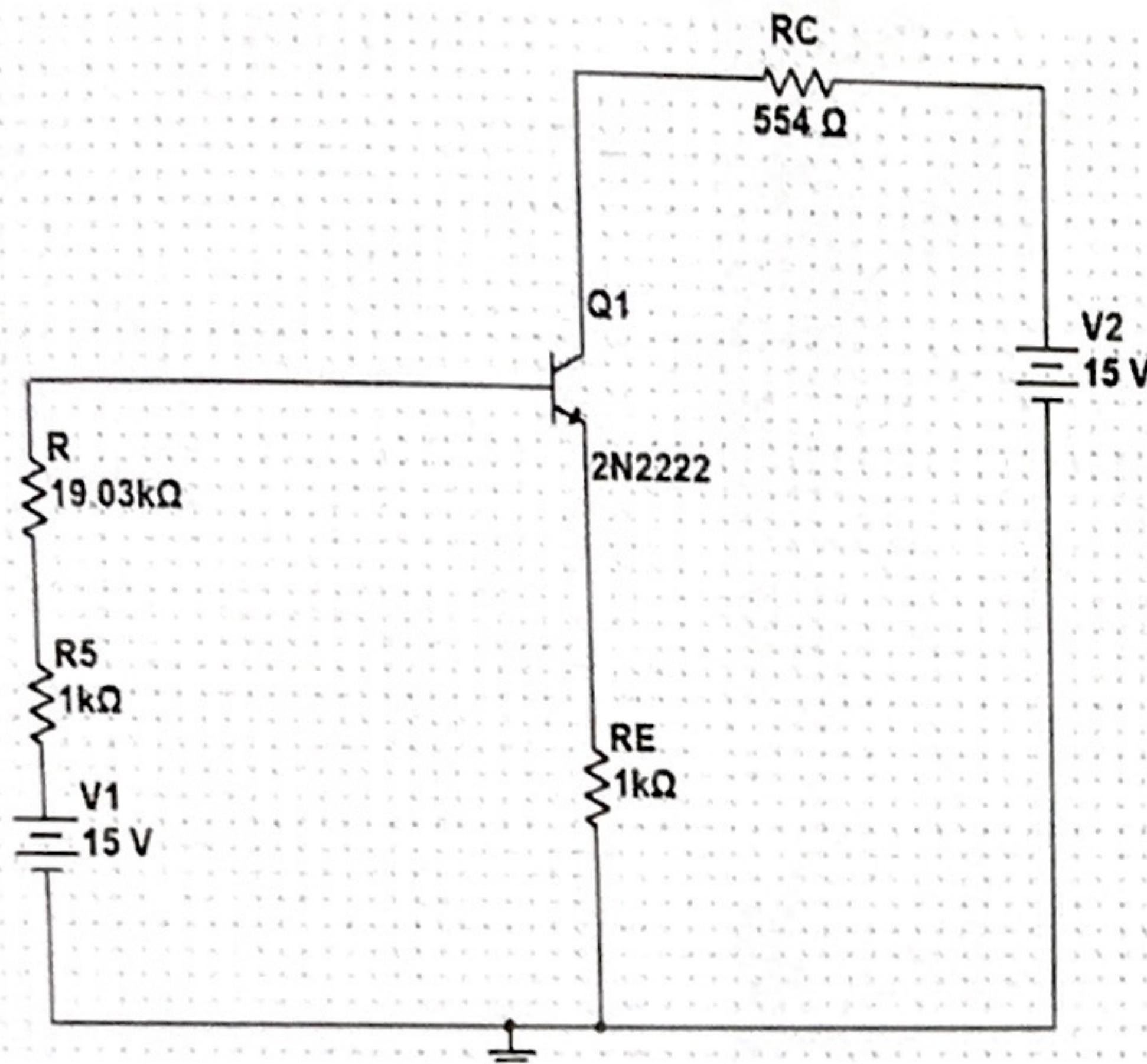
Figure 1(c)

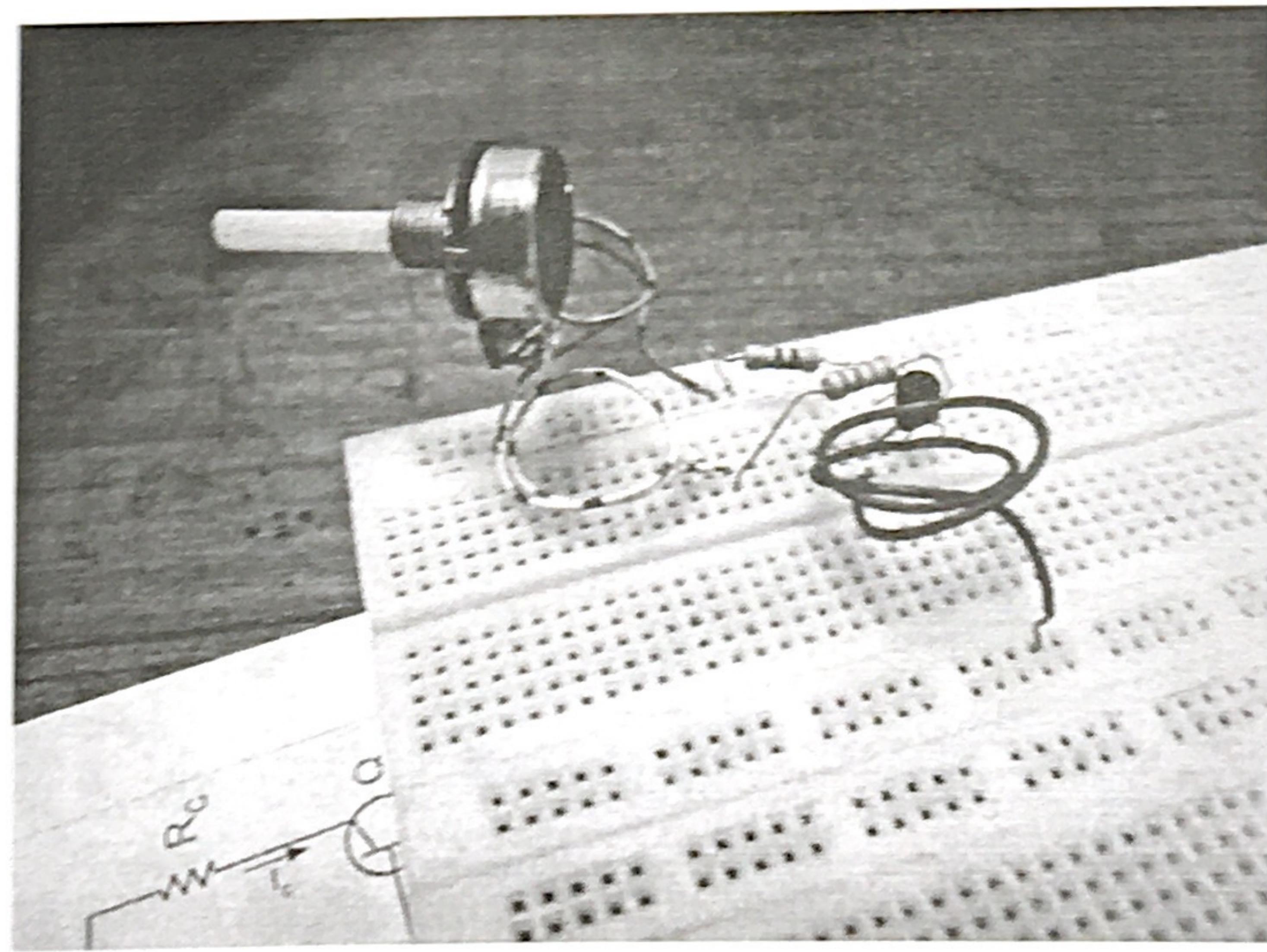
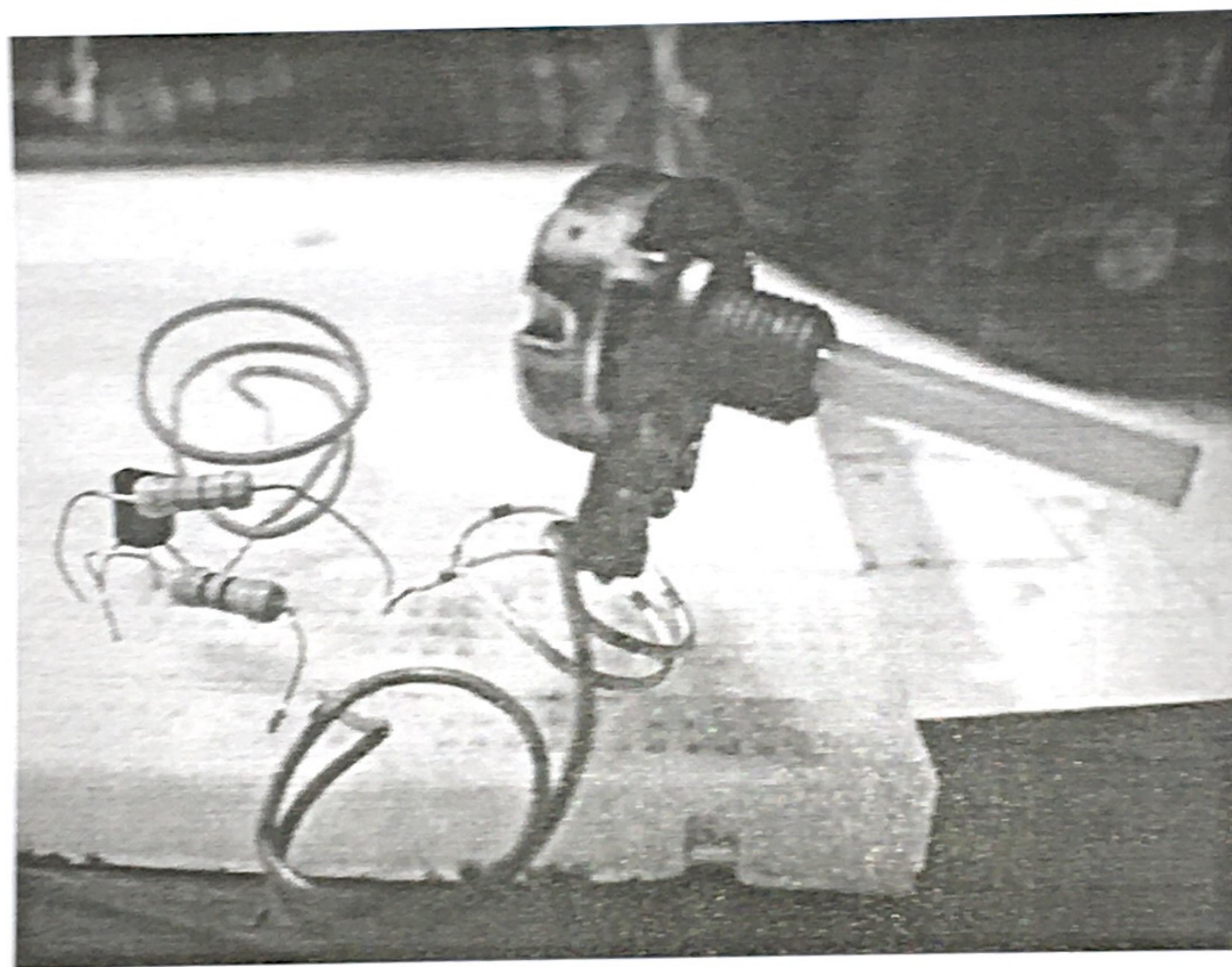
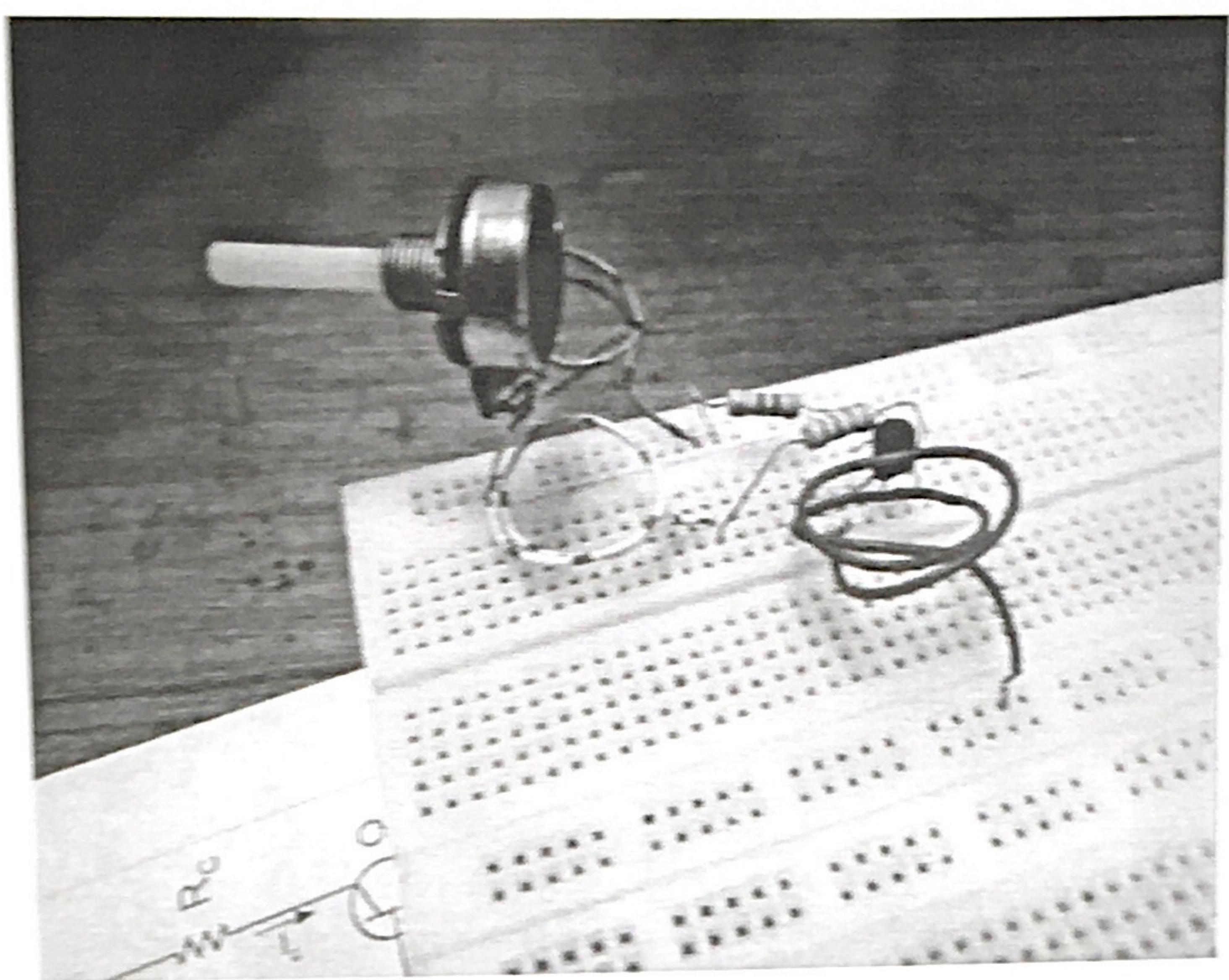
Experimental Procedure:

1. The value of R_C was measured by using multimeter.
2. The value of β was measured by using a multimeter for each transistor.
3. The fixed bias circuit with transistors was constructed.
4. 500k potentiometer was adjust until V_{CE} was equal to $V_{CC}/2$.
5. V_{CE} , V_{BE} and V_{RE} was measured and after that calculated I_C from V_{RE} and R_C . Also I_B was calculated from I_C .
6. Then replaced the first transistor by second one and repeated the step 5.
7. The fixed bias circuit was constructed and repeated step 4, 5, 6.
8. Same will constructed with self bias and over again.

Date Table:

	β	V_{CE}	V_{BE}	V_{RE}	I_C	I_B
Figure 1(a)	93	7.5	0.3	7.8	1.92	0.02
	230	7.8	0.7	7.2	2.08	0.009
	59.567	3.61	5.147	7.697	8.697	55.7
Figure 1(b)	93	7.5	0.7	3.3	4.54	0.04
	230	7.5	0.6	3.4	4.41	0.012
	59.567	0.7	14.287	2.947	2.947	701
Figure 1(c)	93	7.56	0.74	2.93	5.11	0.05
	230	7.5	0.63	3.23	4.64	0.02
	59.567	0.7927	14.971	9.371	9.191	607





Question For Report Writing:

1 Answer: Biasing makes the output circuit more stable for different values of β .

2 Answer: From the table, it is clear that the $\% \Delta$ change of the labeled values is less for 1(b) than 1(a). Hence, stability of circuit 1(b) is more than 1(a). With rise in β , V_{CE} rises while V_{BE} and V_{RE} decrease.

3 Answer: From the table above, it is clear that the $\% \Delta$ change for the values are less with 2(b) being more stable than 2(a) and rise in β causes increase in V_{CE} while V_{BE} and V_{RE} decreases same as 1(a) and 1(b).

4 Answer: Compared to fixed-biased, self-biased circuit are more stable as the $\% \Delta$ differences in values are seen to be less for 2(a) and 2(b) than for 1(a) and 1(b). This is due to the presence of an emitter resistor.

5 Answer: Stability refers to less changes in values of β -Q point means more stable circuit. Q point stands for quiescent point which is merely the DC operating point of the circuit.

Discussion and Conclusion:

1. All apparatus were checked before the start of the experiment. We avoid short connections can produce heat which can be harmful for the components and damage the component.
2. The experimental results were slightly different from the simulated result which could happen due to improper connection, contact resistance and variation of source power.
3. From the data it can be concluded that self biased circuit are more stable then fixed-biased circuit.

References:

1. American International University-Bangladesh (AIUB) Electronic Device Lab manual.
2. A.S. Sedra, K.C. Smith, Microelectronic Circuits, Oxford University Press (1998)
3. J. Keavn, ORCAD PSpice and Circuit Analysis, Prentice Hall Press (2001)
4. P. Horowitz, W. Hill, The Art of Electronics, Cambridge University Press (1989)